## Application/Control No. Applicant(s)/Patent Under Reexamination 10/807,437 PARK ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Toniae M. Thomas 2822 **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY US-2002/0045318 A1 04-2002 CHEN et al. 438/303 US-2003/0045061 A1 03-2003 В Kwon et al. 438/303 С US-2004/0063289 A1 04-2004 Ohta, Hiroyuki 438/303 08-2004 D US-2004/0155269 A1 Yelehanka et al. 257/288 08-2004 Ε US-2004/0157457 A1 Xu et al. 438/694 F US-2005/0116360 A1 06-2005 Huang et al. 257/900 US-6,359,321 B2 03-2002 G Shimizu et al. 257/412 US-6,924,180 B2 08-2005 н Quek, Elgin 438/163 1 US-USκ US-US-US-**FOREIGN PATENT DOCUMENTS** Document Number Date Country Code-Number-Kind Code Country Name Classification MM-YYYY Ν 0 Р Q S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) W

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